

Feasibility of T/R Module Functionality in a Single SiGe IC

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SiGe Single-Chip T/R Program

1990's

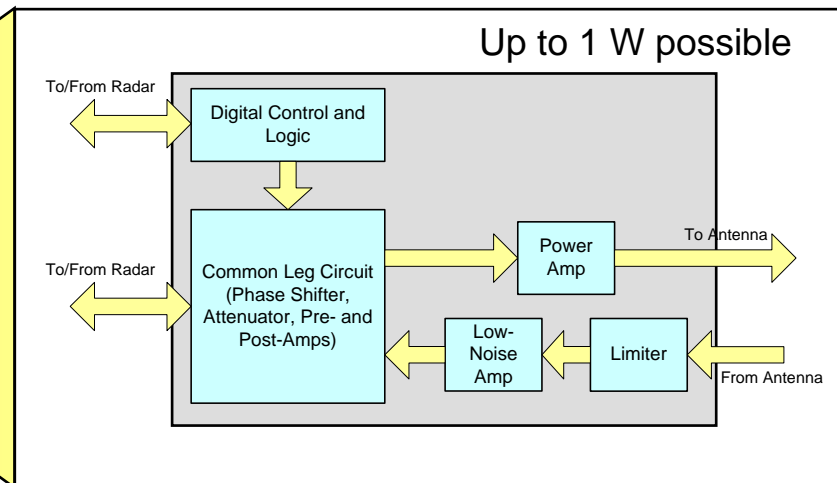
- ◆ Multi-chip module
- ◆ Expensive (~ \$1000)
- ◆ High power
- ◆ Cost drivers:
 - ◆ MMIC area
 - ◆ Touch labor
 - ◆ Packaging



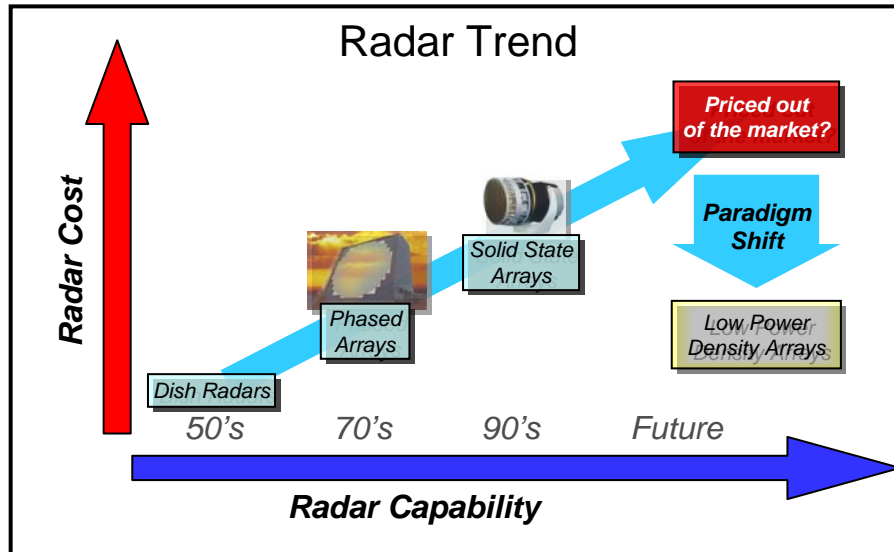
- ◆ GTRI and GEDC co-development
- ◆ Full Transmit/Receive module functionality in a single chip
- ◆ Currently developing devices
- ◆ Integrated chips to be available in FY07

Future

- ◆ Single chip "module"
- ◆ Cheap (< \$10)
- ◆ Low power
- ◆ New cost paradigm:
 - ◆ Multi-chip panel architecture
 - ◆ Spread labor and package cost over many "modules"



Redefining Future Radar Technology



Low Power Density (LPD) Paradigm Shift

1990's

Future

- Multi-chip module
- Expensive (~ \$1000)
- High power
- Cost drivers:
 - MMIC area
 - Touch labor
 - Packaging

- Single chip "module"
- Cheap (< \$10)
- Low power
- New cost paradigm:
 - Multi-module panel architecture
 - Spread labor and package cost over many "modules"

Low Power Density Benefits

Large LPD antennas reduce cost and system footprint

10 W per element
20 m² aperture

6 Trailers
300 gal/hr

Conventional

100 W per element
9.3 m² aperture

21 Trailers
1500 gal/hr

Higher Power Density

1 W per element
43 m² aperture

1 Trailer
50 gal/hr

Low Power Density

Key:

- Heat Exchanger
- Power Generator
- Antenna & Electronics
- Fuel Rate
- Antenna Cost

Georgia Tech Research

Multi-Panel Array (DARPA)

Single Chip T/R (MDA)

Emerging Low-Cost SiGe (IRAD + MDA)

Packaging Techniques (MDA)

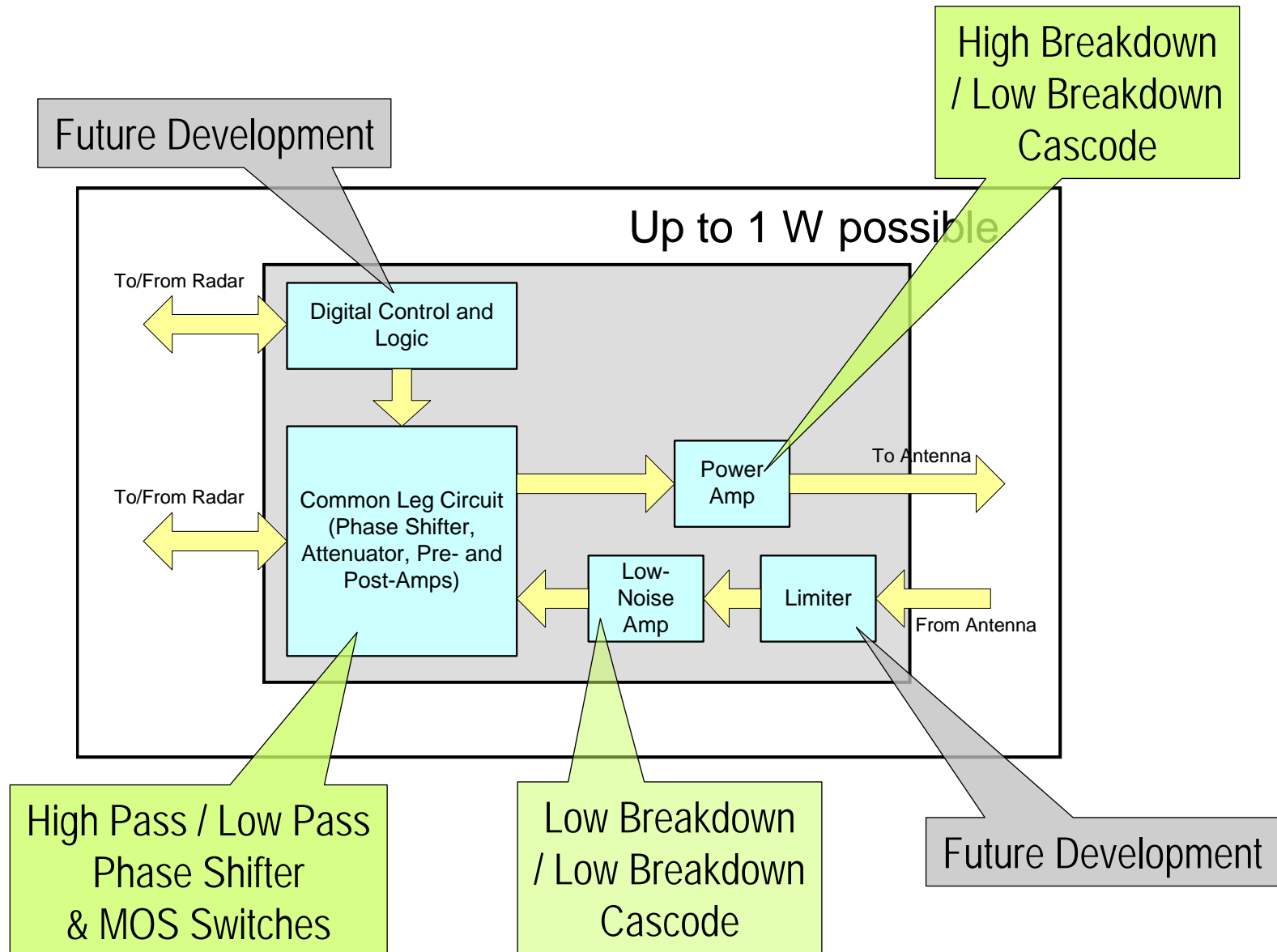
Multi-Chip Panel

RF Apertures (DARPA)

Deployable Apertures (MDA)

Alignment and Calibration (MDA)

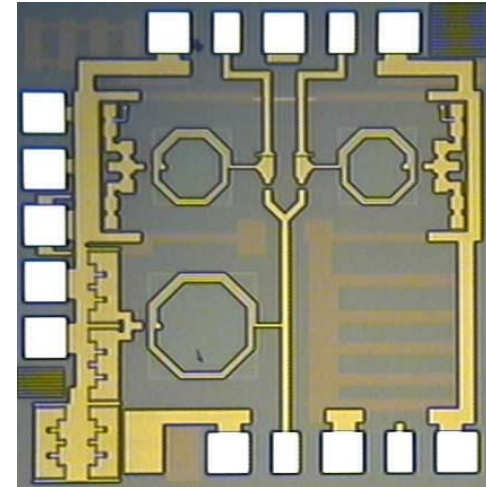
SiGe T/R Chip Development





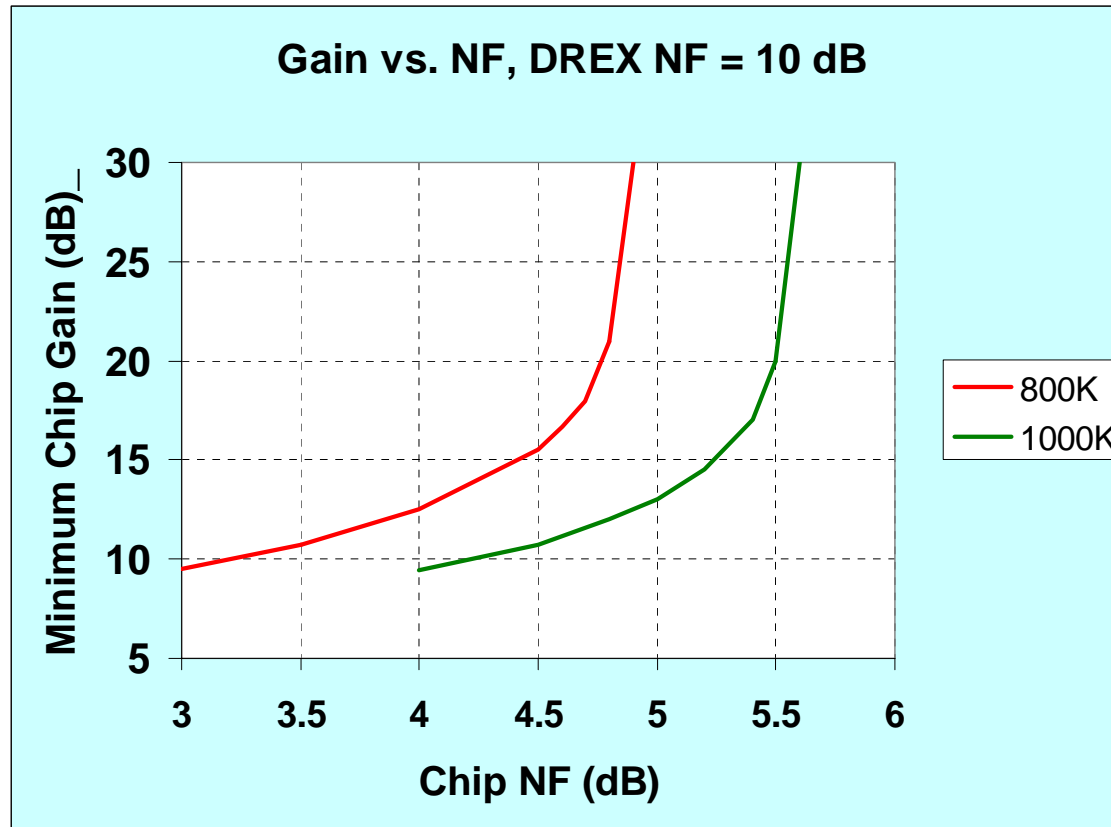
Accomplishments to Date

- ✓ Developed detailed T/R chip requirements
- ✓ Developed preliminary design
- ✓ Reviewed and Analyzed preliminary design
- ✓ Trade off design, specifications, and performance
- ✓ Designed and fabricated critical components
- ✓ Tested components



Gain / Noise Figure Requirements

- ◆ Requirements based on:
 - ◆ Overall system noise temperature of 800K (Objective) 1000K (Threshold)
 - ◆ Assumed Digital Receiver/Exciter (DREX) input NF = 10 dB



Phase Shifter Bit Requirements

At least 4 bits
required for
negligible gain loss

Number of Bits, N	Gain Loss (dB)
2	-1.000
3	-0.229
4	-0.056
5	-0.014
6	-0.003

Increase to 5 bits
preferable for low
sidelobe
performance

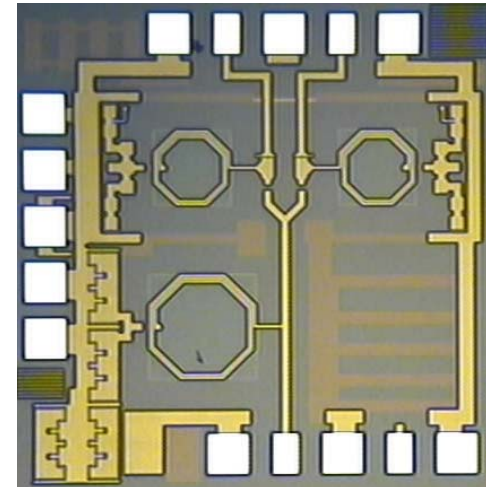
Number of bits	Minimum bit size (degrees)	RMS Phase Error (degrees)
2	90	26.0
3	45	13.0
4	22.5	6.5
5	11.25	3.2
6	5.625	1.6
7	2.8125	0.8

4-bit threshold and 5-bit objective requirements selected



Component Results to Date

- ✓ Hi Pass / Lo Pass Phase Shifter
- ✓ MOS Switches
- ✓ Cascode LNA
- ✓ Cascode Pre Amp
- ✓ Cascode Power Amp

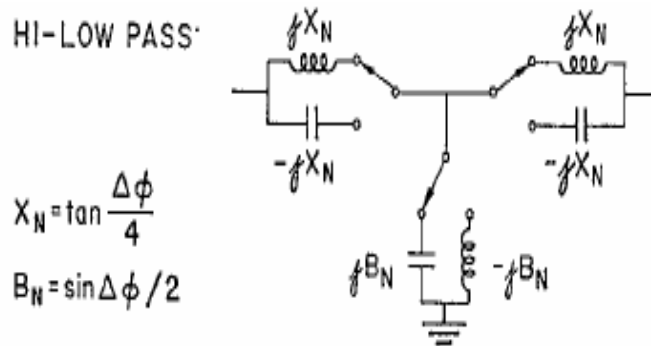


Hi-Low Pass Shifter

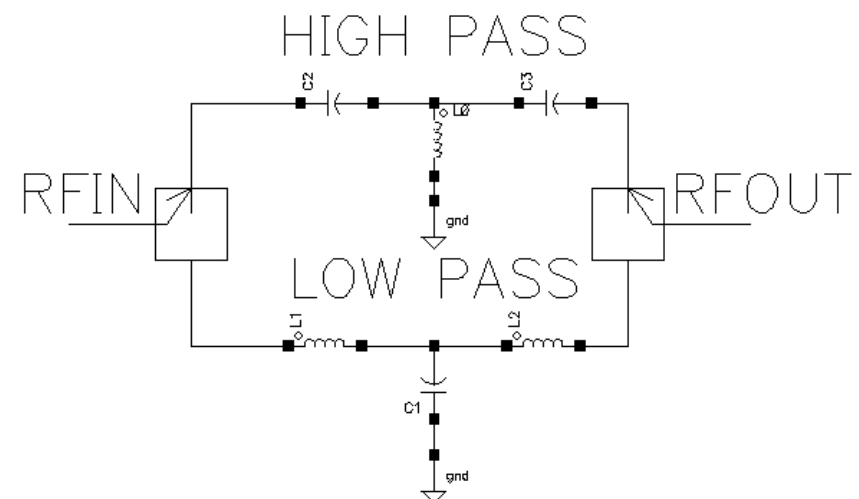


- Hi-Low pass phase shifter provides flat phase response
- Shift is relative phase between low pass and high pass
- Very broadband and easier to control than reflection shifter
- Higher values of shift require more elements
- Switch and filter sections can be designed independently
(if filter and switch $S_{11} < -20$ dB)

Hi-Low Pass Schematic

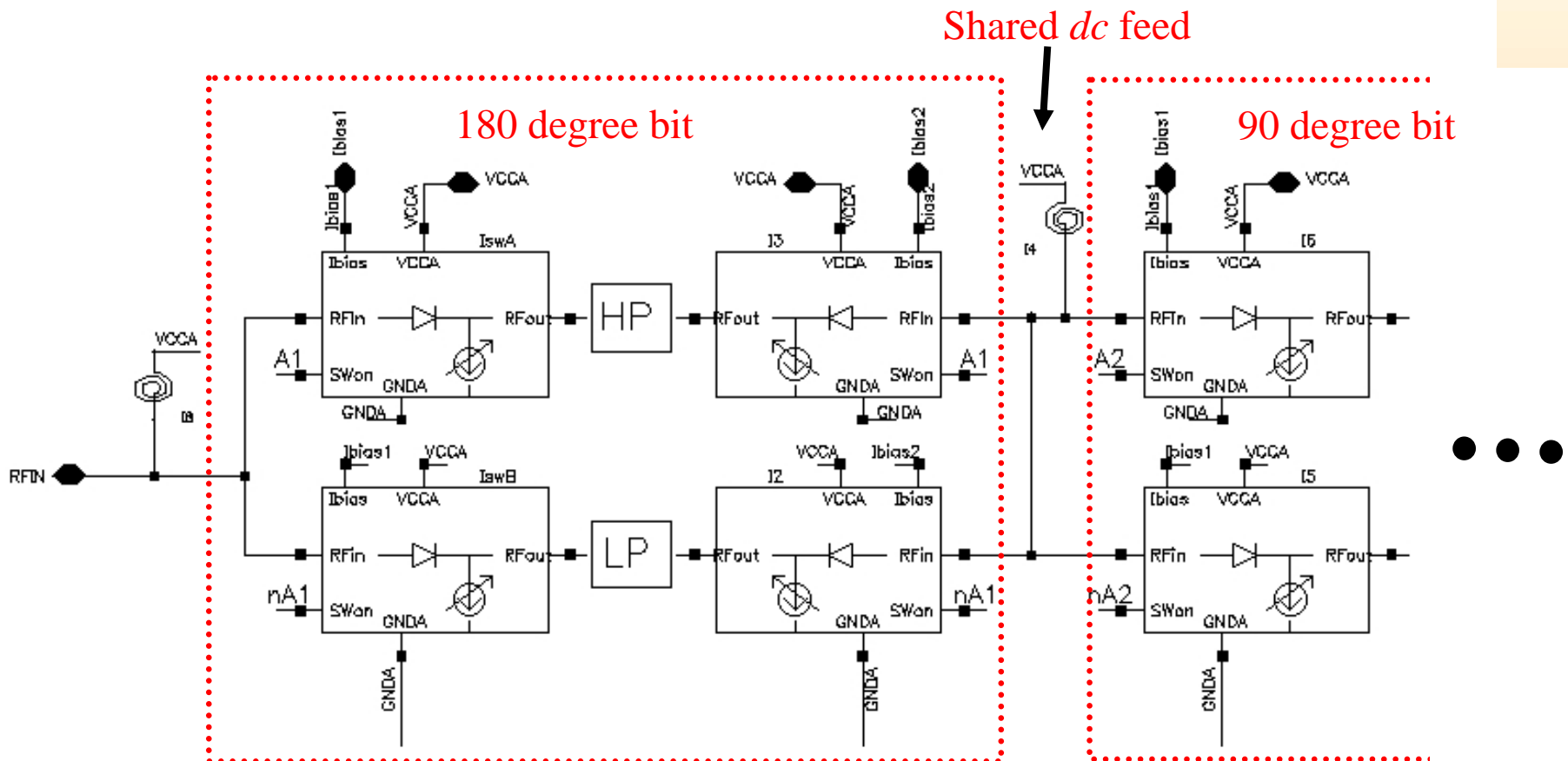


Alternative Topology



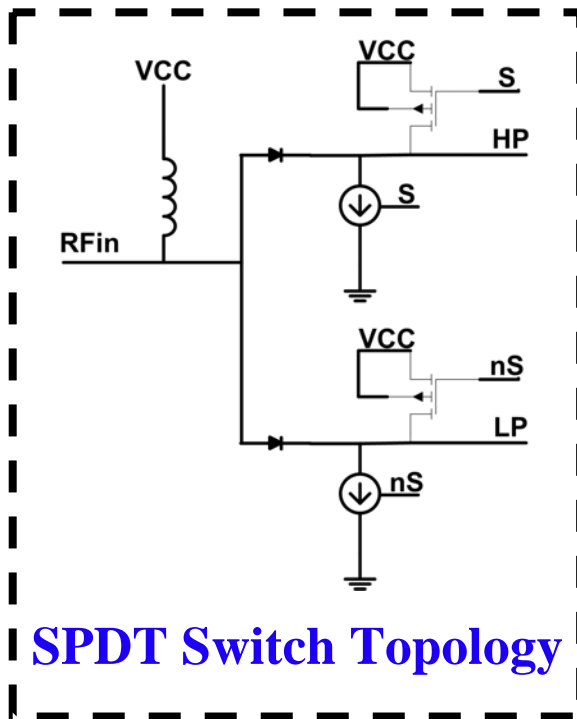
N-bit Hi-Low Pass Shifter

- Bits may be chained together if well matched
- Mismatched bits cause large phase error
- *dc* feeds shared in between bits



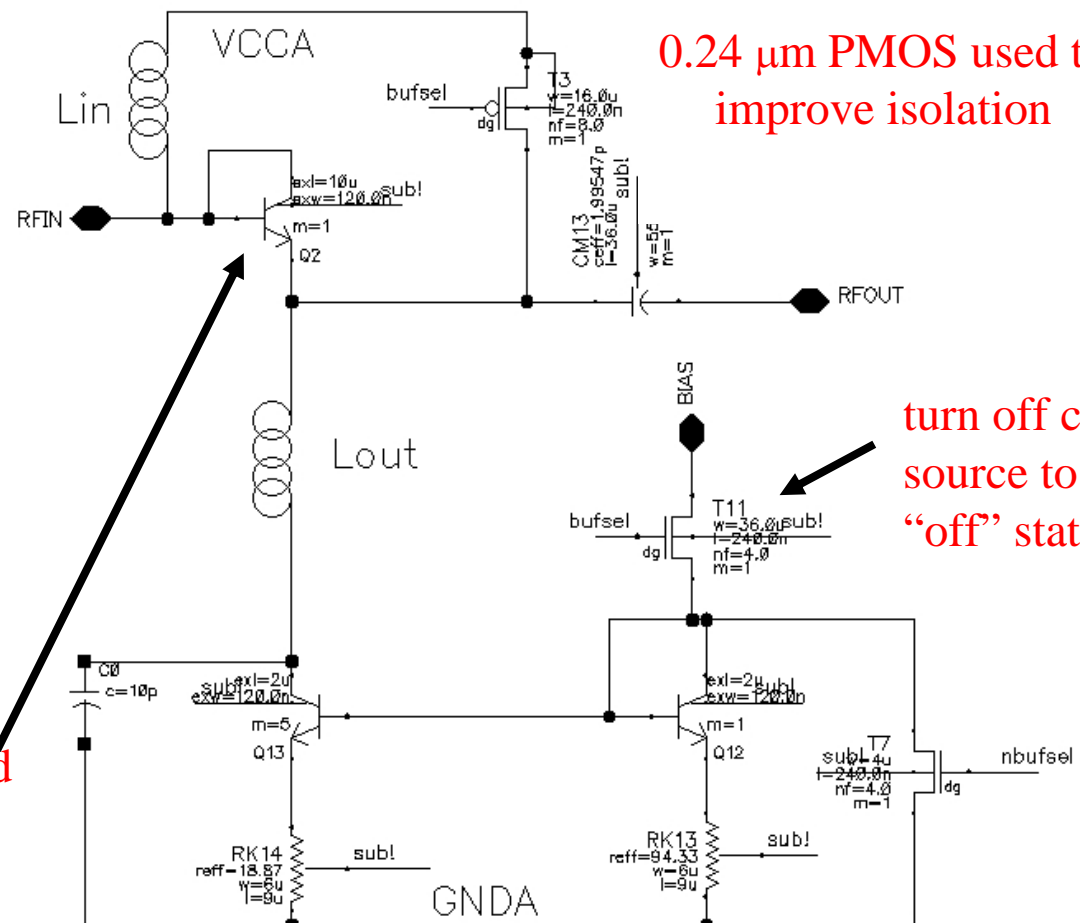
Diode Switch Design

• Series Connected HBT Diode Element for SPDT Switch



SPDT Switch Topology

use of diode connected HBT npn instead of schottky or PIN diode



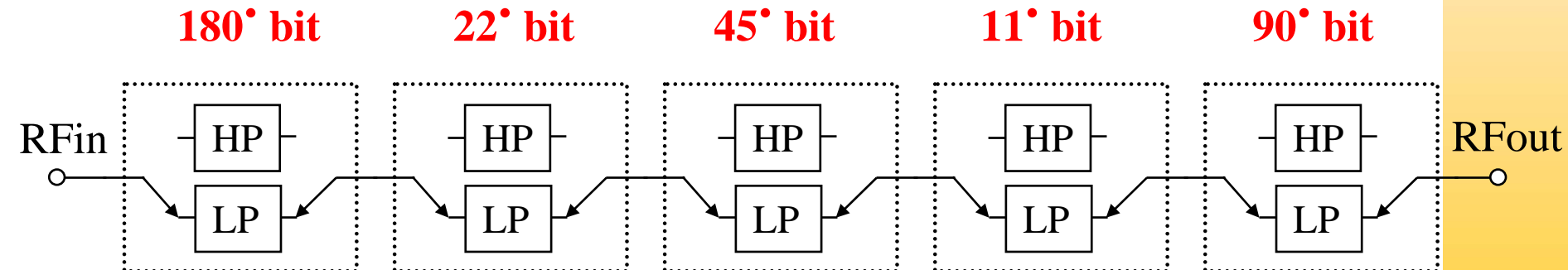
0.24 μm PMOS used to improve isolation

turn off current source to create "off" state

Bit Ordering



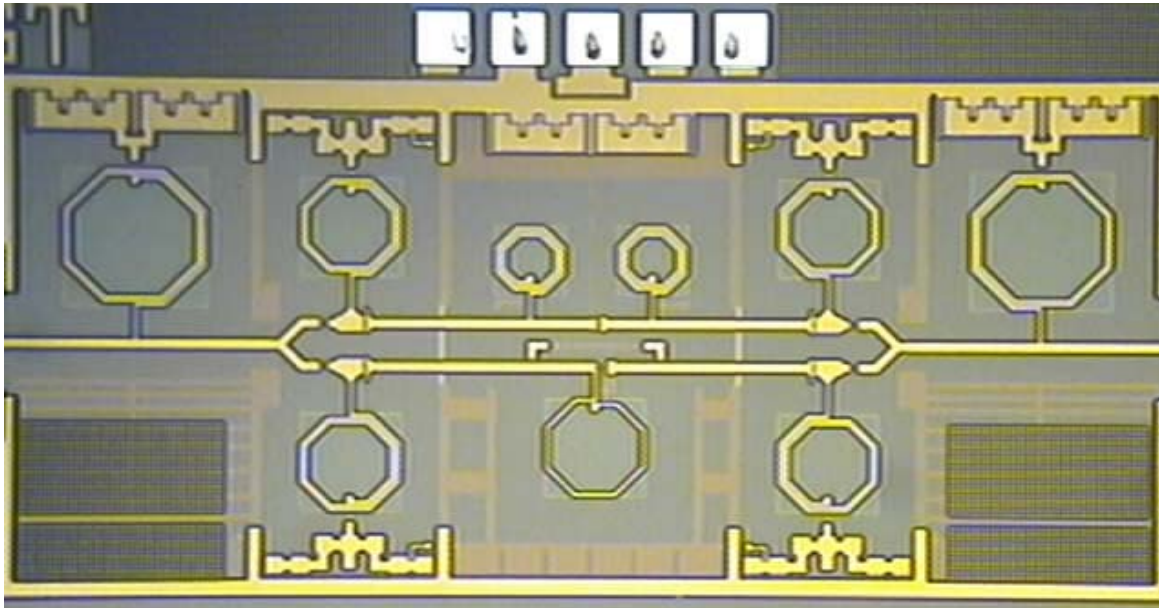
- Higher shift value bits are easily matched ($S_{11} < -25$ dB)
- Smaller bits require smaller element values on low pass
 - Parasitics cause unpredictable shift and impedance match
 - Bits can be optimized with higher values at cost of match
- Best performance when poorly matched bits are separated
- Our best bit order is: $180^\circ - 22^\circ - 45^\circ - 11^\circ - 90^\circ$



Preliminary Results

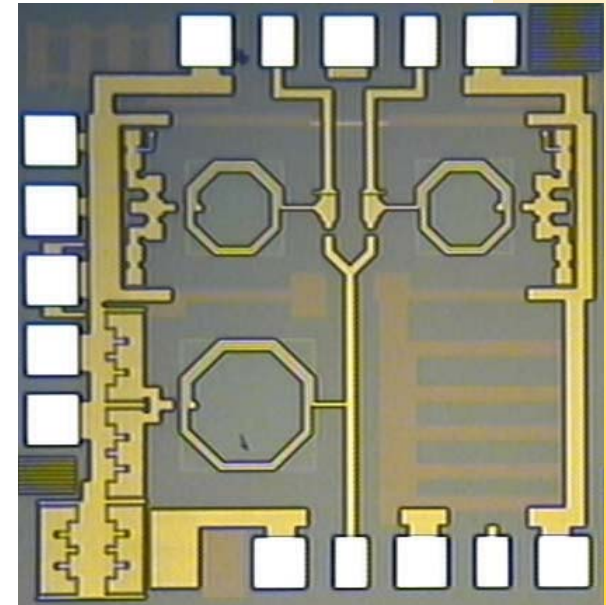
- 90° Section of Shifter and SPDT HBT Switch Fabricated
- Hardware from Jan 05 Tapeout
- Preliminary Designs

90° Section of Shifter



2.56 x 1.2 mm²

SPDT HBT Switch



1.2 x 1.2 mm²

Preliminary Results

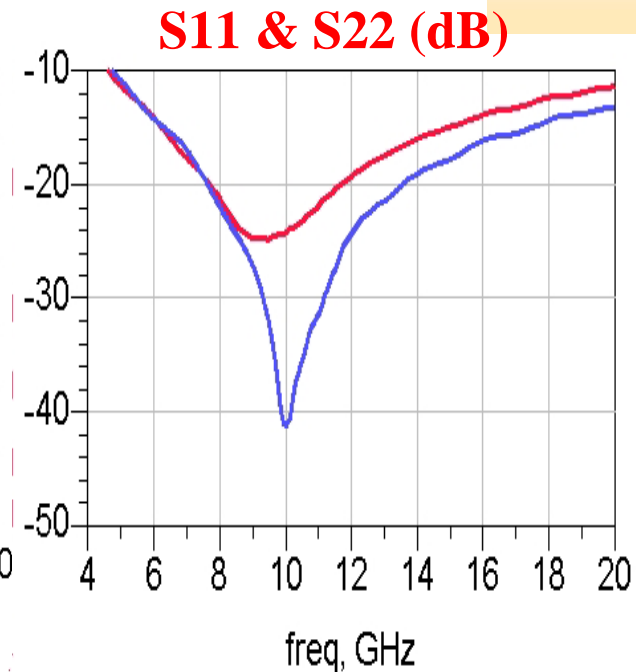
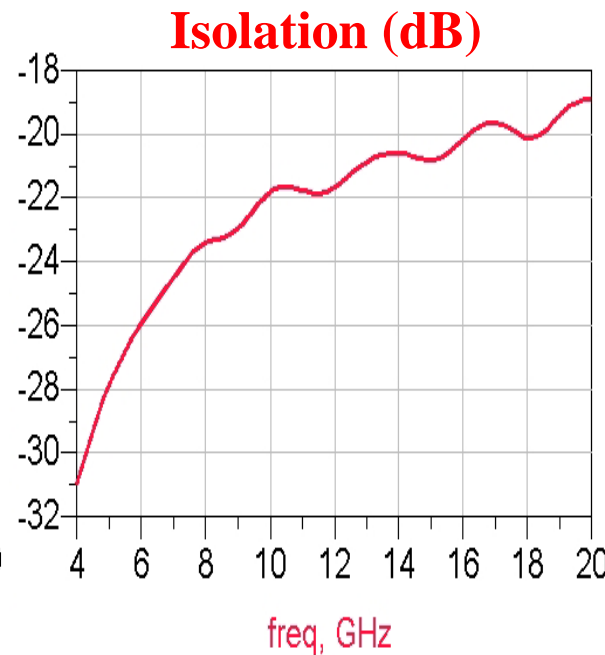
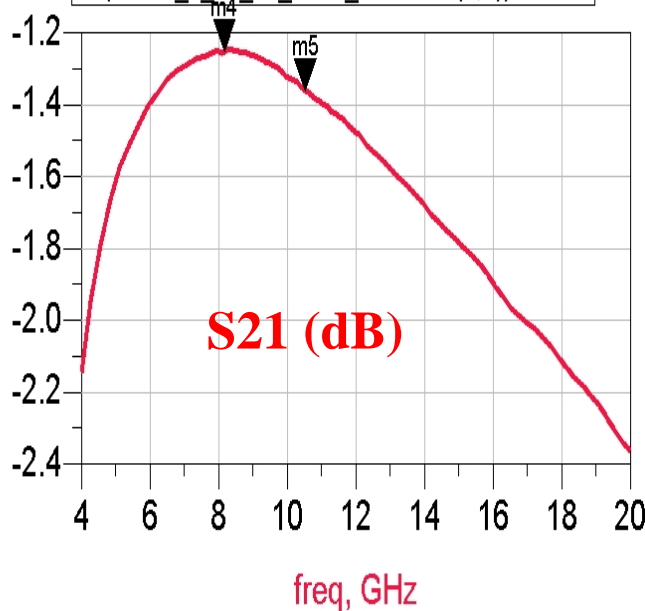
- Single HBT Diode NPN Switch Fabricated and Tested
- Sim Results: $IL < 0.92$ dB, $RL > 19$ dB, $Iso > 20$ dB, $IIP3 = 24$ dBm

dc: $V_{cc} = 2.1$ V, $I_{bias} = 1.8$ mA, $I_{cc} = 8.75$ mA

Measured $IIP3 \sim 20$ dBm

Measured $IP_{1dB} \sim 3$ dBm

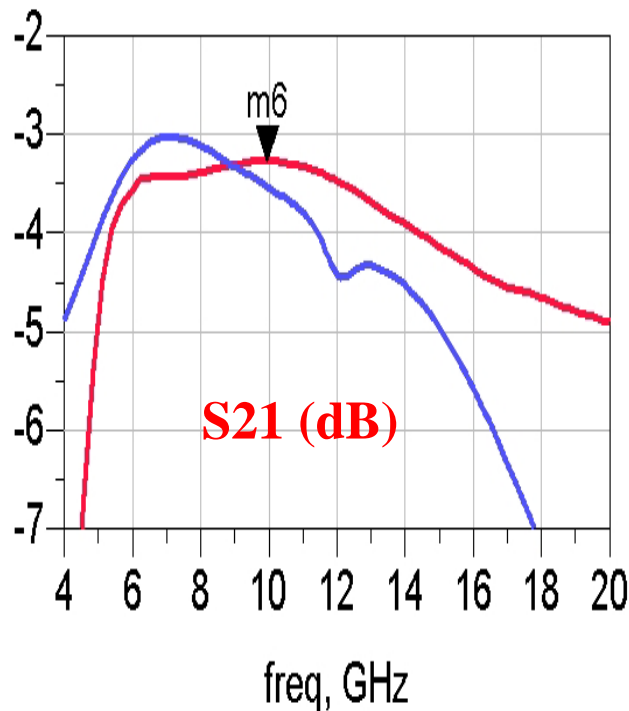
m5
freq=10.53GHz
dB(Jan05_5_12_05_trans_switch..S(2,1))=-1.359
m4
freq=8.163GHz
dB(Jan05_5_12_05_trans_switch..S(2,1))=-1.250



Preliminary Results

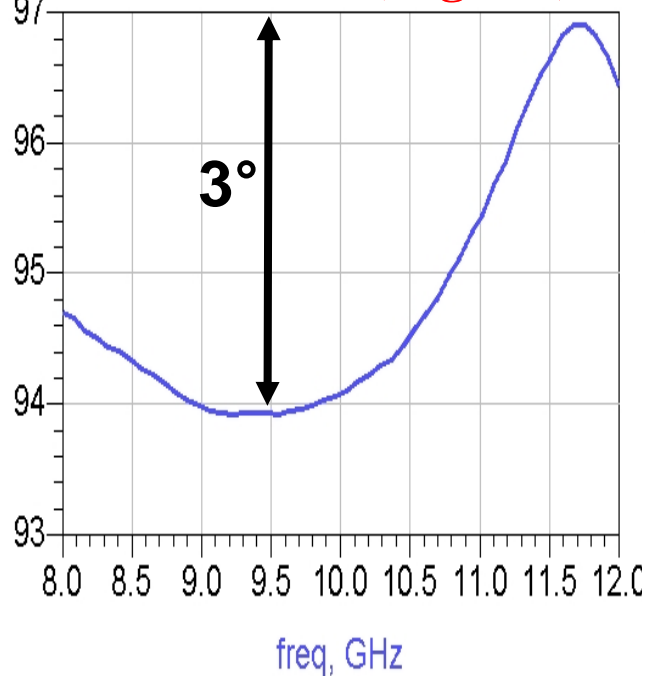
- 90° Section of Shifter Fabricated & Tested
- Sim. Results: IL = 2.1 dB, RL > 15, Phase Shift = 90° +/- 3°

m6
freq=9.959GHz
dB(Jan05_5_12_05_2vbias_shifter..S(2,1))=-3.281

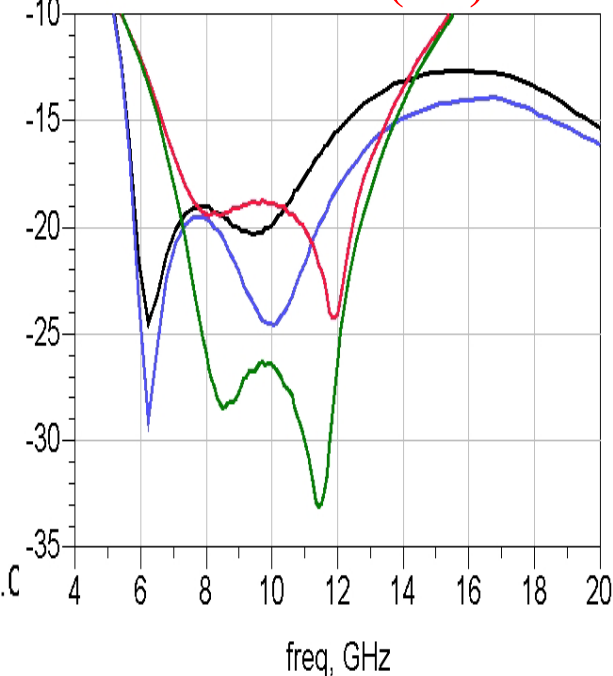


dc: $V_{cc}=2.1V$, $I_{bias1} = I_{bias2} = 1.8mA$,
 $I_{cc} = 17.4 mA$

Phase Shift (degrees)

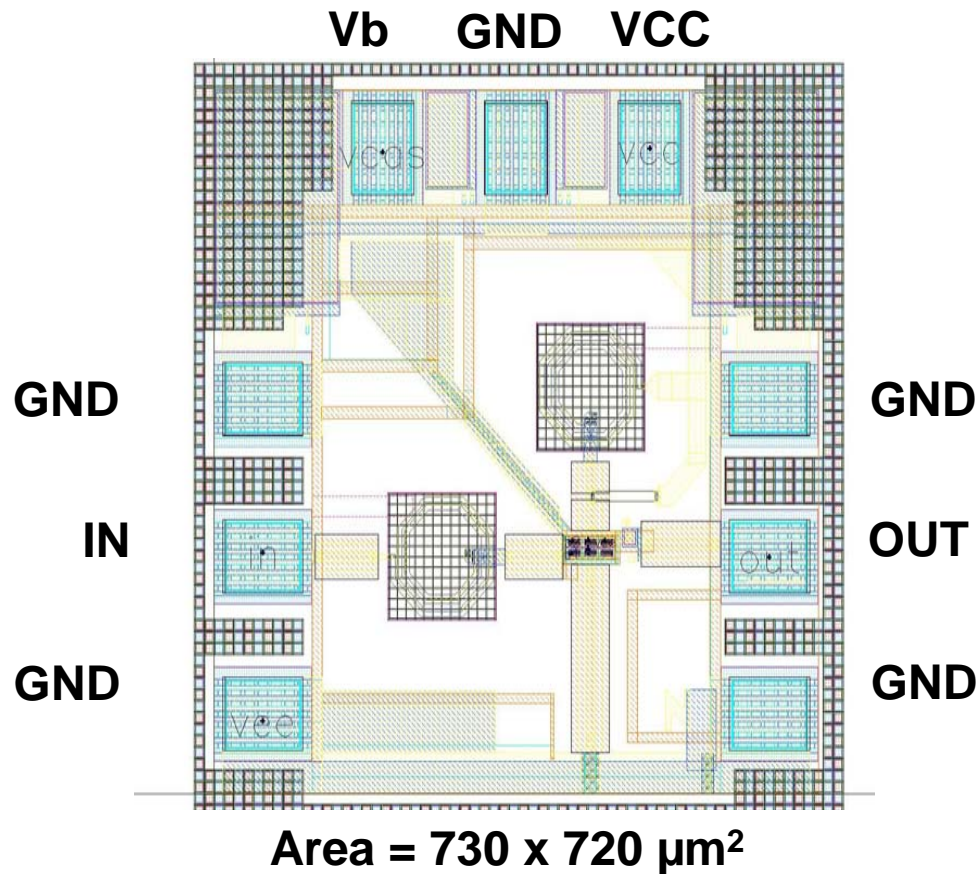


S11 & S22 (dB)



SiGe LNA

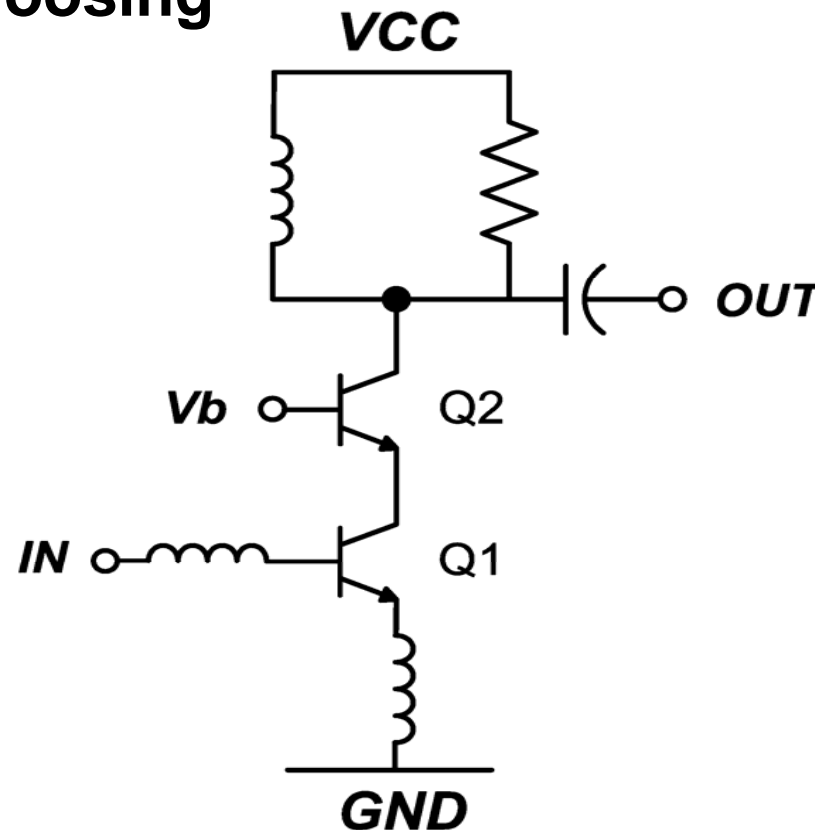
- Layout and bias conditions



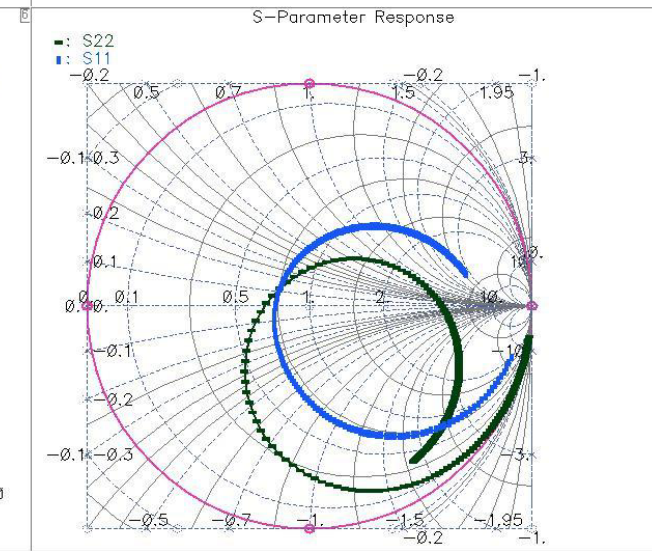
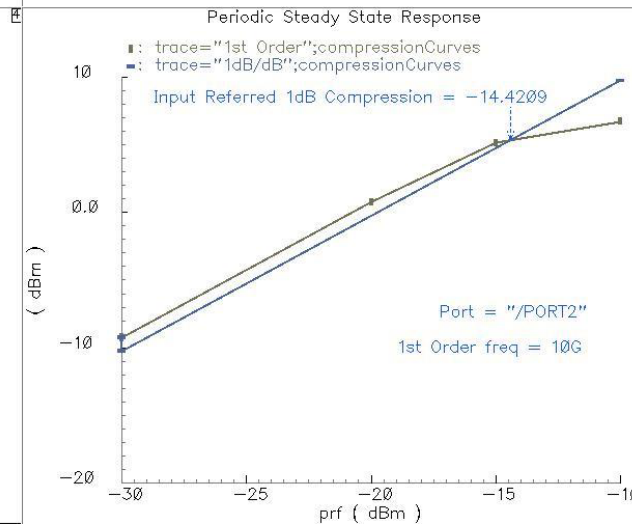
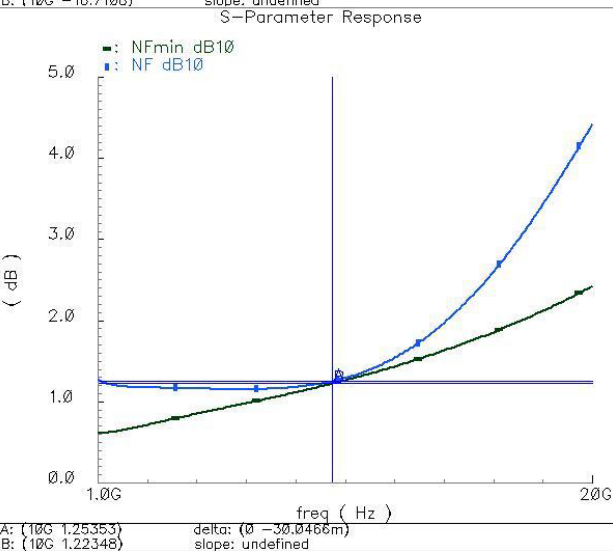
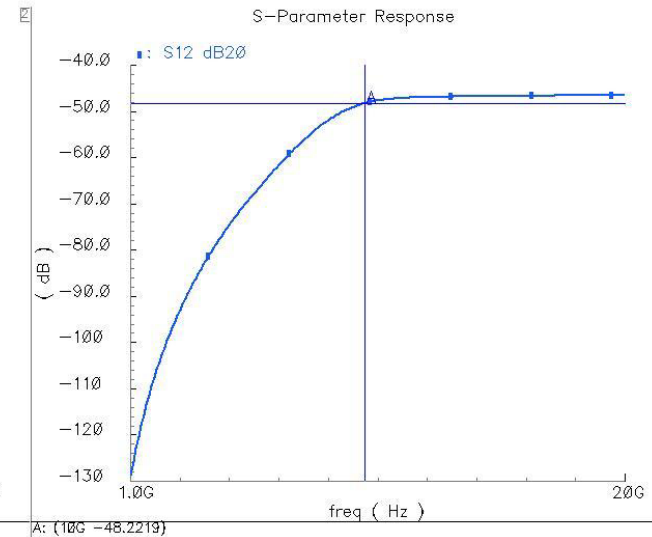
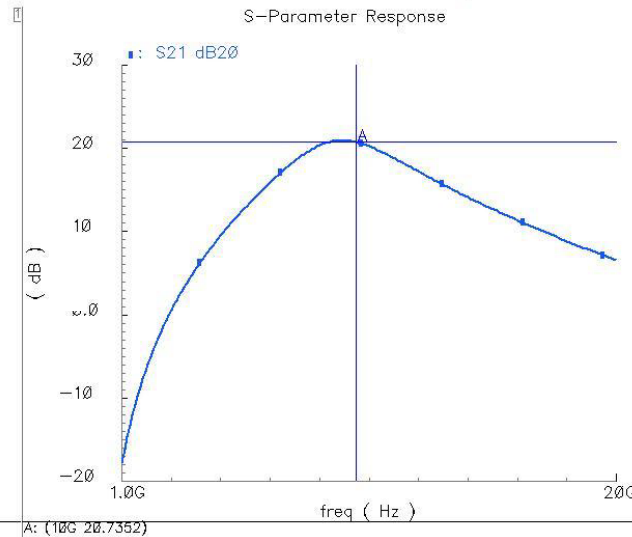
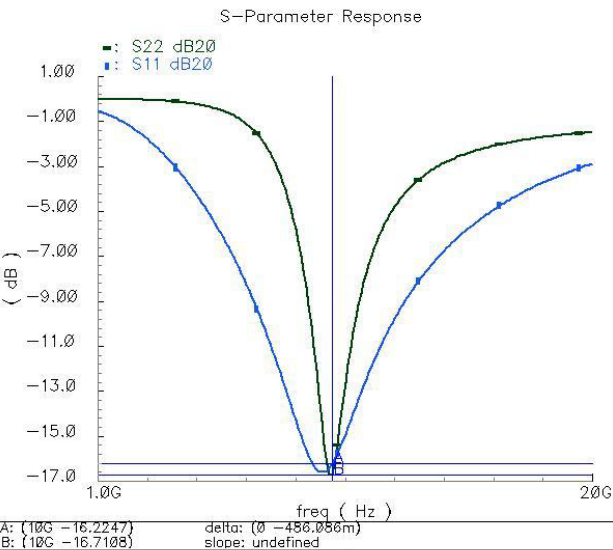
VCC	2.5 V
Vb	2 V
GND	0 V
Ib	14 μA
Ic	6 mA



- **Cascode topology**
 - suppresses feedback and improves stability
- **Noise and impedance match by choosing**
 - emitter length
 - collector current
 - base inductor
 - emitter inductor
- **NF/gain/IIP3 tradeoff**



SiGe LNA

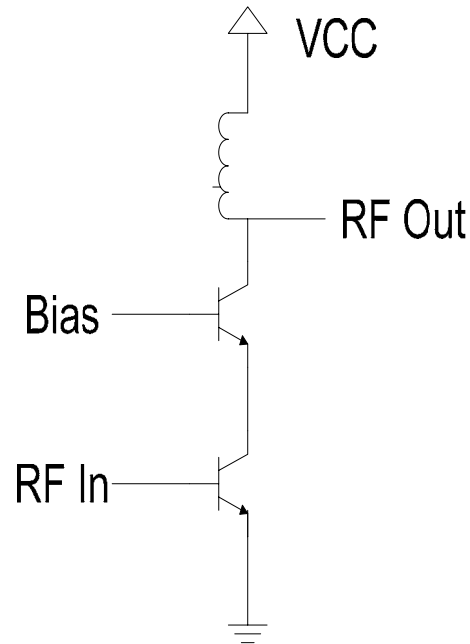
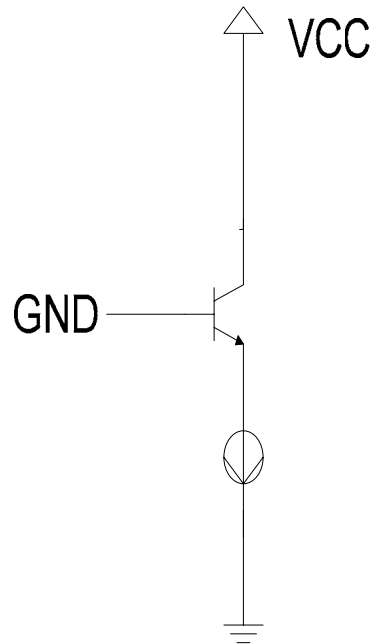




- **Simulated performance summary**

Frequency	10 GHz
S11	< -16 dB
S22	< -16 dB
S21	> 20 dB
NF	< 1.3 dB
Input P1dB	> -15 dBm

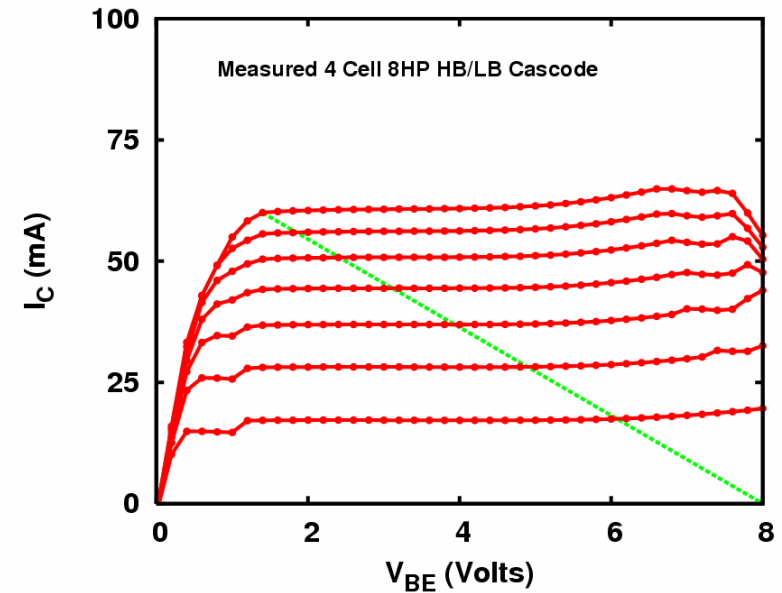
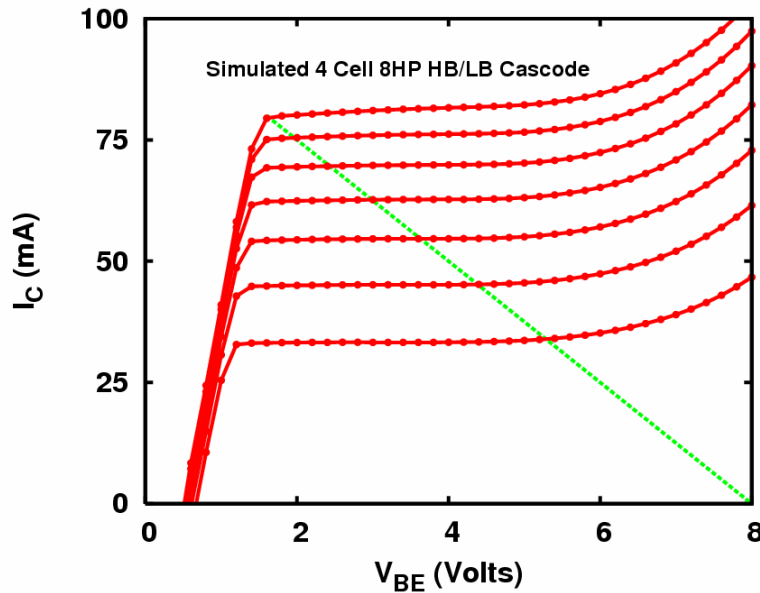
Extend PA Voltage Range



- Forced Emitter Current
- Breakdown Approaches BVCBO
- Improves DCIV Linearity

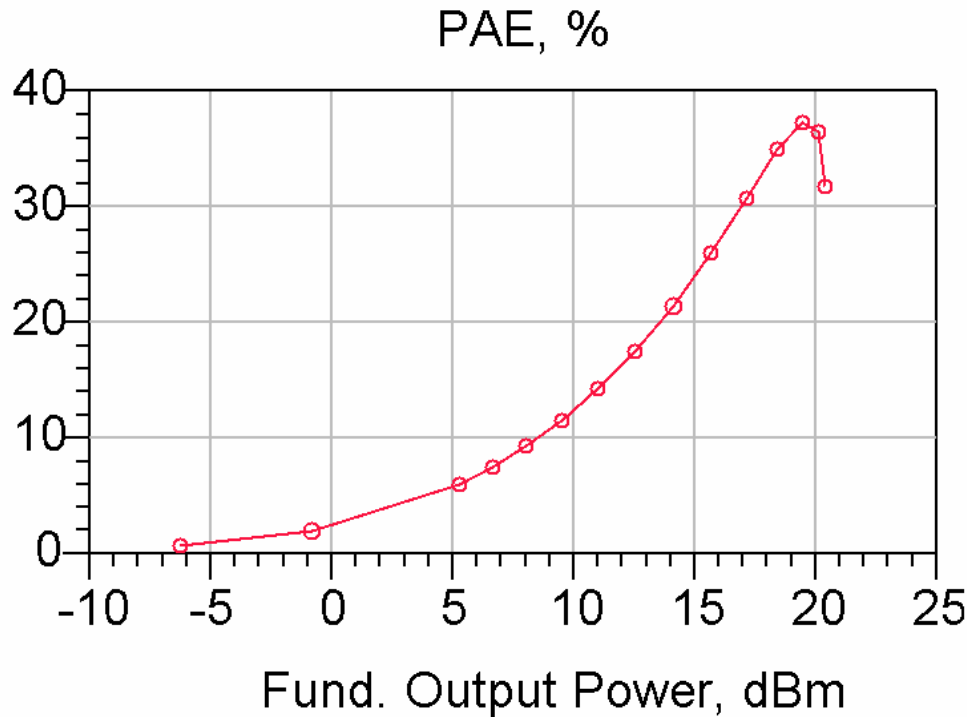
- Circuit Realization of Forced I_E
- Upper bias is AC ground
- RF input on lower base

Cascode PA Characteristics



- Simulated vs. Measured 4 Cell 8HP 0.12x18 HB / 0.12x5 LB
- Slight Beta difference between model and simulation
- Beta compression and breakdown characteristics similar
- Knee voltage equal to $V_{BE} + V_{CESat}$

Simulated Results



8HP Cascoded Devices

- 12 parallel load pull cells
- Post layout extraction
- Realistic on chip Qs
- Non-optimized for harmonics

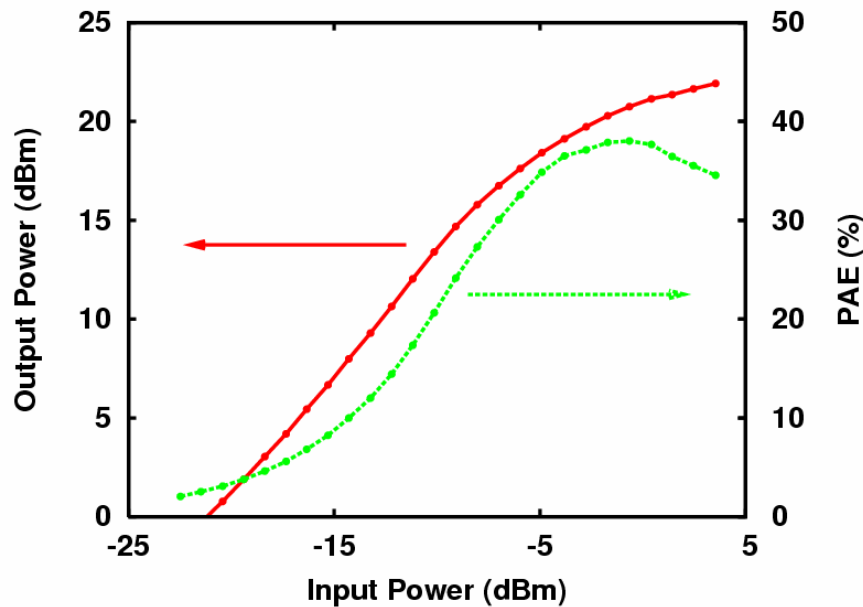
Strong Class AB Results

- 19 dBm output power
- 25 dB of gain
- 38% PAE

• Interconnects modeled using T-line models

- Show .1 dB of loss for 500 um run of 40 um wide line

Preliminary PA Results



- **8HP Cascoded Devices**
 - 12 parallel load pull cells
 - Non-optimized for harmonics and layout
 - Slightly mismatched source
- **Strong Class AB Results**
 - 21 dBm output power
 - 20 dB of gain
 - 38% PAE

- Meets power spec, promising efficiency for pre-driver
- ~150 total cascode cells to reach 30 dBm with margin for passive losses

Summary

- ◆ MDA/AS Radar System Technology panel investing in SiGe RF devices for future radar needs
- ◆ SiGe single-chip T/R program
 - ◆ 4-year development plan (FY05-FY08)
 - ◆ First integrated T/R chips in FY07
 - ◆ Requirements developed (FY05)
 - ◆ Critical devices designed and analyzed (FY05)
 - ◆ Some devices fabricated and tested (FY05)
 - ◆ More fabrication runs underway (due back late FY05)
 - ◆ Critical risk reduction for low power density apertures
- ◆ *SiGe Single-chip T/R for Radar appears feasible*

